ETX-700

Temperature/Humidity Test Report

Report NO: 07E020028

Issued by:	Rex Chang	/	*08/23/2007*
	Test Engineer		**Date**
Reviewed by:	Wenyuan Yang	/	*08/23/2007*
	Manager		**Date**

Test item list

Test Product: ETX-700 A0.4 + ECB-901A A1.0-A

Sample Configuration & Quantity Under Test:

1. CPU: Onboard AMD LX-800 / 500MHz (Bios Ver.T0.0L)
2. Chipset: AMD S5536AD + ITE 8888G
3. VGA: Integrated in AMD LX
4. Test Software: Windows XP / Run PassMark Burn In Test Pro 4.0
5. ETX Evaluation Board: ECB-901A A1.0-A
6. Heat Sink:

Sample 1: (AT Power)

1. Memory: Transcend 512MB / V58C2512804SBI5I (DDR-333)
2. CFD: PQI 32MB
3. HDD: Seagate ST3400014A 40GB
4. AT Power Supply: Zippy SP2-4300F

Sample 2: (ATX Power)

5. Memory: Transcend 512MB / V58C2512804SBI5I (DDR-333)
6. CFD: PQI 32MB
1. HDD: Seagate ST3400014A 40GB
2. ATX Power Supply: Seventeam ST-350EAG-05G

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Temp./humidity power on/off test

Test Date: 08-22~23-2007

Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

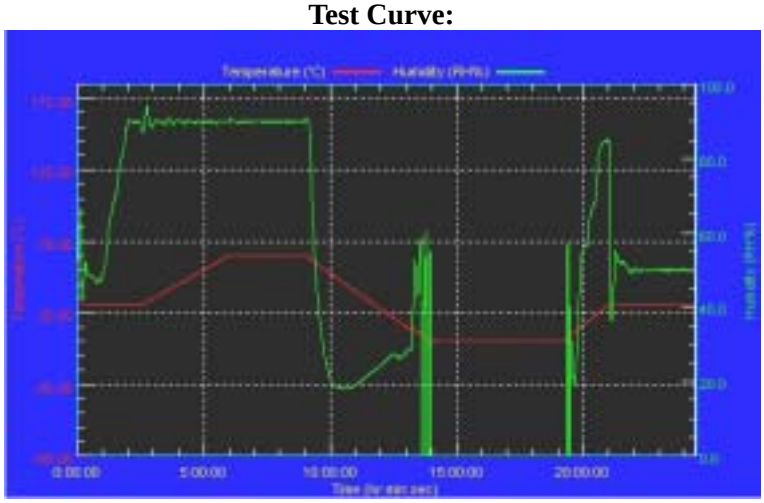
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 11/17/06
Serial Number: 2582

Temperature & Humidity Power On/Off Test:

Testing Specification:

Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

Sample 1: (AT Power)

No problem was found during the Temperature & Humidity Power On/Off Test..

Sample 2: (ATX Power)

No problem was found during the Temperature & Humidity Power On/Off Test..

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Temperature variation operation test

Test Date: 08-21~22-2007

Test Site: AAEON QA Internal Lab.

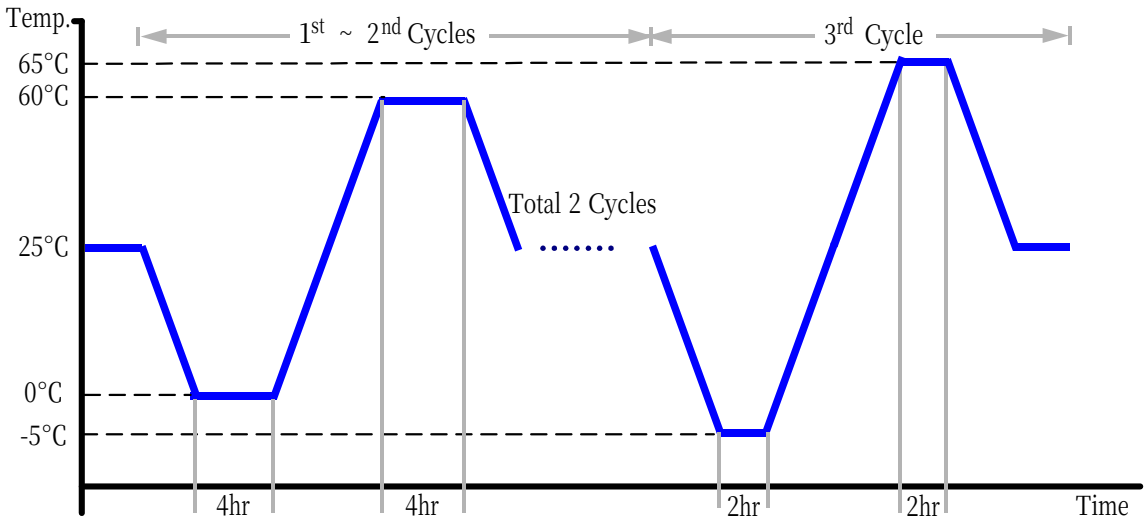
Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 11/17/06
Serial Number: 2582

Temperature & Humidity Cycle Test:

1. Test Low Temperature: 0°C (1~2 cycles)
   -5°C (3rd cycle)
2. Test High Temperature: 60°C (1~3 cycles)
   65°C (3rd cycle)
3. Test dwell time: 4Hrs (1~2 cycles)
   2Hrs (3rd cycle)
4. Temperature slope: 2°C/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



Test Result:

Sample 1: (AT Power)

No problem was found during the temperature variation operation test.

Sample 2: (ATX Power)

No problem was found during the temperature variation operation test.

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Cold start and hot start test

Test Date: 08-20-2007

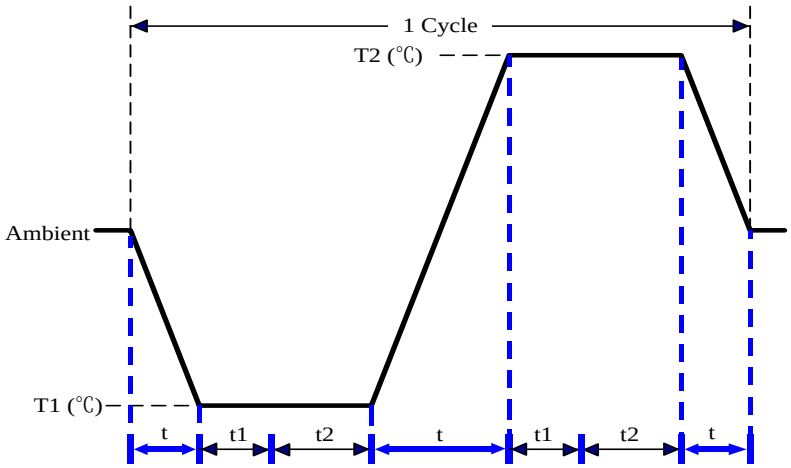
Test Site: AAEON QA Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 11/17/06
Serial Number: 2582

Test Condition:



Parameters	Description
T1	-5℃
T2	65℃
t1	1 hrs
t2	2 hrs
t	2℃/min
n (Cycle)	1

t = temprature slope
t ~ t1: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
Test Software:Windows XP

Test Result:

Sample 1: (AT Power)

a. No problem was found during the cold start test.
b. No problem was found during the hot start test.

Sample 2: (ATX Power)

a. No problem was found during the cold start test.
b. No problem was found during the hot start test.

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